

### Description

LPN1010C use advanced FSMOS™ technology to provide low  $R_{DS(on)}$ , low gate charge, fast switching and excellent avalanche characteristics. This device is specially designed to get better ruggedness and suitable to use in Synchronous-rectification applications.

◆ $V_{DS,min}$	100V
◆ $I_{D,pulse}$	210A
◆ $R_{DS(ON),max}@V_{GS}=10V$	10m $\Omega$
◆ $R_{DS(ON),max}@V_{GS}=4.5V$	14m $\Omega$
◆ $Q_g$	72nC

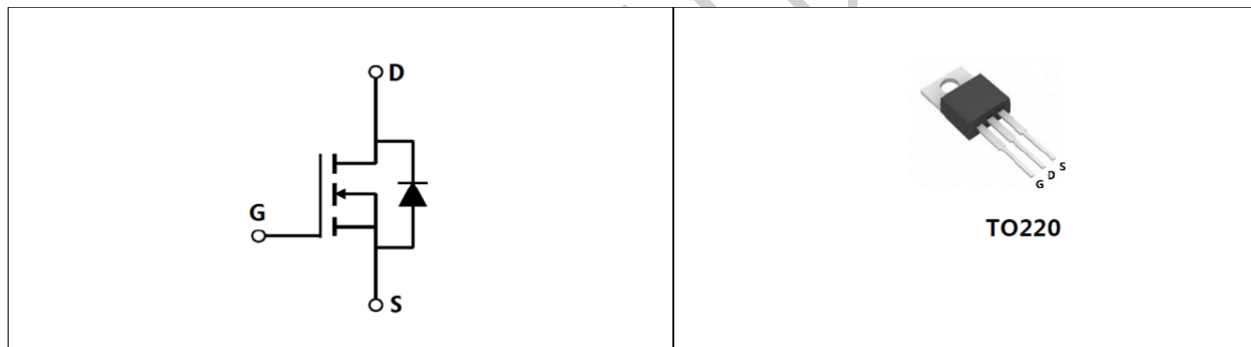
### Features

- Low  $R_{DS(on)}$ &FOM
- Extremely low switching loss
- Excellent stability and uniformity
- Fast switching and soft recovery

### Applications

- Consumer electronic power supply
- Motor control
- Synchronous-rectification
- Isolated DC/DC convertor
- Invertors

### Schematic and Package Information



Schematic Diagram

Pin Assignment Top View

### Ordering Information

Package	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Box/Carton Box	Units/Carton Box
TO220	50	20	1000	6	6000

### Product Information

Product	Package	Pb Free	RoHS	Halogen Free
LPN1010C	TO220	yes	yes	yes

**Absolute Maximum Rating** at  $T_j=25^\circ\text{C}$  unless otherwise noted

Parameter	Symbol	Value	Unit
Drain source voltage	$V_{DS}$	100	V
Gate source voltage	$V_{GS}$	$\pm 20$	V
Continuous drain current <sup>1)</sup>	$I_D$	70	A
Pulsed drain current <sup>2)</sup>	$I_{D,pulse}$	210	A
Power dissipation <sup>3)</sup>	$P_D$	330	W
Single pulsed avalanche energy <sup>5)</sup>	$E_{AS}$	100	mJ
Operation and storage temperature	$T_{stg}, T_j$	-55 to 150	$^\circ\text{C}$

**Thermal Characteristics**

Parameter	Symbol	Value	Unit
Thermal resistance, junction-case	$R_{\theta JC}$	0.38	$^\circ\text{C/W}$
Thermal resistance, junction-ambient <sup>4)</sup>	$R_{\theta JA}$	62.5	$^\circ\text{C/W}$

**Electrical Characteristics** at  $T_j=25^\circ\text{C}$  unless otherwise specified

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Drain-source breakdown voltage	$BV_{DSS}$	100			V	$V_{GS}=0V, I_D=250\mu A$
Gate threshold voltage	$V_{GS(th)}$	1.0		2.5	V	$V_{DS}=V_{GS}, I_D=250\mu A$
Drain-source on-state resistance	$R_{DS(on)}$			10.0	m $\Omega$	$V_{GS}=10V, I_D=10A$
Drain-source on-state resistance	$R_{DS(on)}$			14.0	m $\Omega$	$V_{GS}=4.5V, I_D=10A$
Gate-source leakage current	$I_{GSS}$			100	nA	$V_{GS}=20V$
				-100		$V_{GS}=-20V$
Drain-source leakage current	$I_{DSS}$			1	$\mu A$	$V_{DS}=100V, V_{GS}=0V$

**Dynamic Characteristics**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Input capacitance	$C_{iss}$		3888.5		pF	$V_{GS}=0V,$ $V_{DS}=100V,$ $f=1MHz$
Output capacitance	$C_{oss}$		273.7		pF	
Reverse transfer capacitance	$C_{rss}$		5		pF	
Turn-on delay time	$T_{d(on)}$		49.6		nS	$V_{GS}=10V,$ $V_{DS}=50V,$ $R_G=25\Omega,$ $I_D=12A$
Rise time	$t_r$		52.5		nS	
Turn-off delay time	$T_{d(off)}$		390		nS	
Fall time	$t_f$		55.2		nS	

**Gate Charge Characteristics**

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Total gate charge	$Q_g$		72		nC	$I_D=12A,$ $V_{DS}=50V,$ $V_{GS}=10V$
Gate-source charge	$Q_{gs}$		8.9		nC	
Gate-drain charge	$Q_{gd}$		18.8		nC	
Gate plateau voltage	$V_{plateau}$		3.2		V	

### Body Diode Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test condition
Diode forward current	$I_S$			70	A	$V_{GS} < V_{th}$
Pulsed source current	$I_{SP}$			210	A	
Diode forward voltage	$V_{SD}$			1.3	V	$I_S = 20A, V_{GS} = 0V$
Reverse recovery time	$t_{rr}$		66.8		nS	$I_S = 12A,$ $di/dt = 100A/\mu S$
Reverse recovery charge	$Q_{rr}$		139		nC	
Peak reverse recovery current	$I_{rrm}$		3.5		A	

### Note

- 1) Calculated continuous current based on maximum allowable junction temperature.
- 2) Repetitive rating; pulse width limited by max. junction temperature.
- 3)  $P_d$  is based on max. junction temperature, using junction-case thermal resistance.
- 4) The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_a = 25^\circ C$ .
- 5)  $V_{DD} = 50V, R_G = 25 \Omega, L = 0.3mH$ , starting  $T_j = 25^\circ C$

## Electrical Characteristics Diagrams

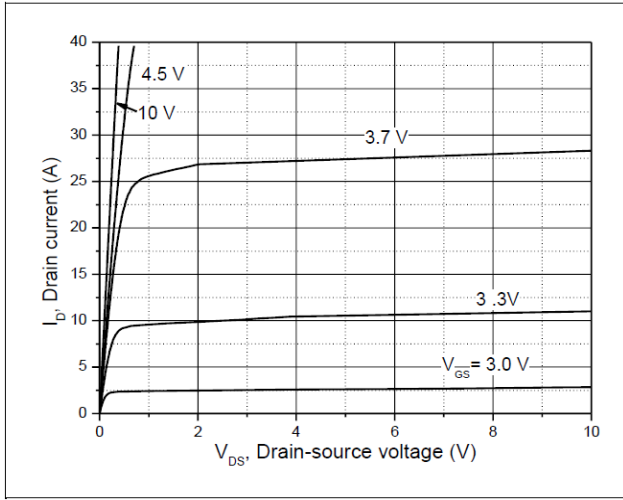


Figure 1, Typ. Output characteristics

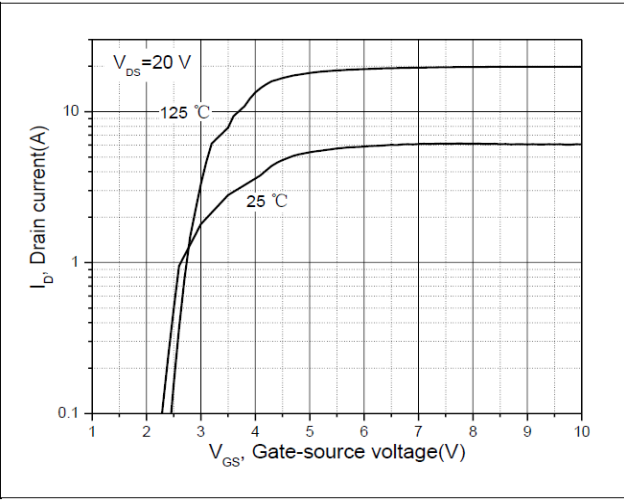


Figure 2, Typ. Transfer characteristics

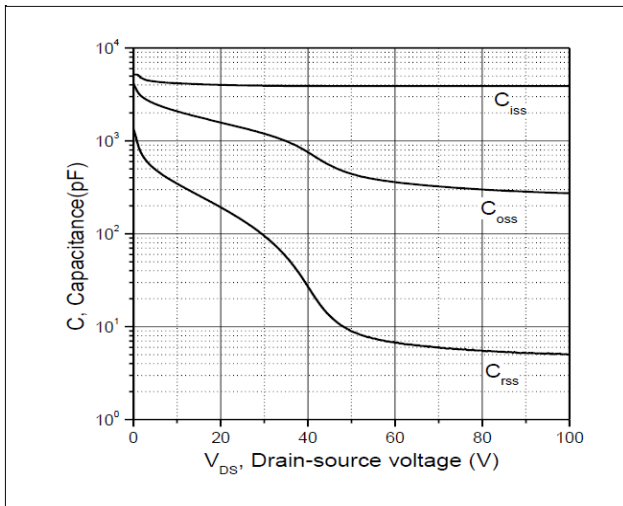


Figure 3, Typ. capacitances

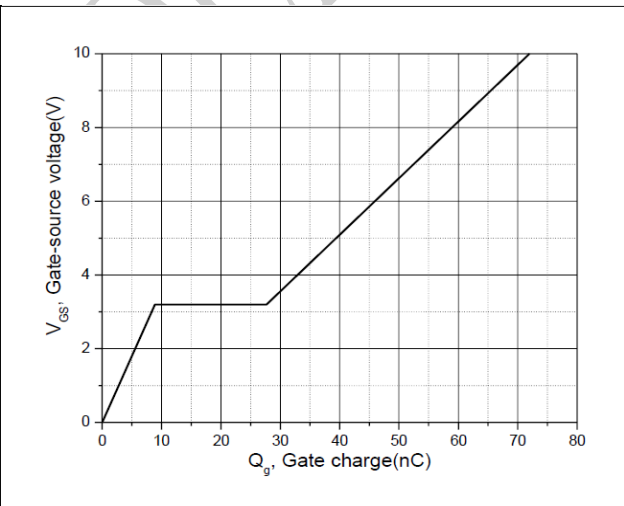


Figure 4, Typ. gate charge

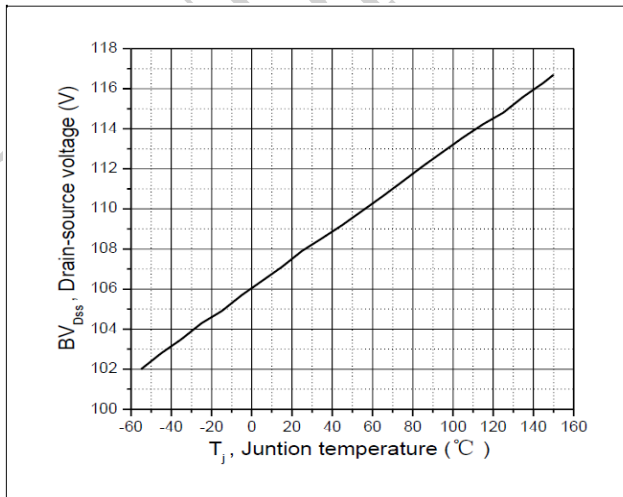


Figure 5, Drain-source breakdown voltage

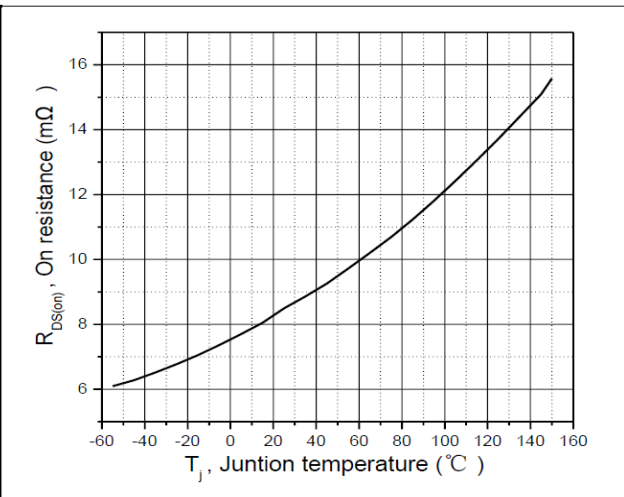


Figure 6, Drain-source on-state resistance

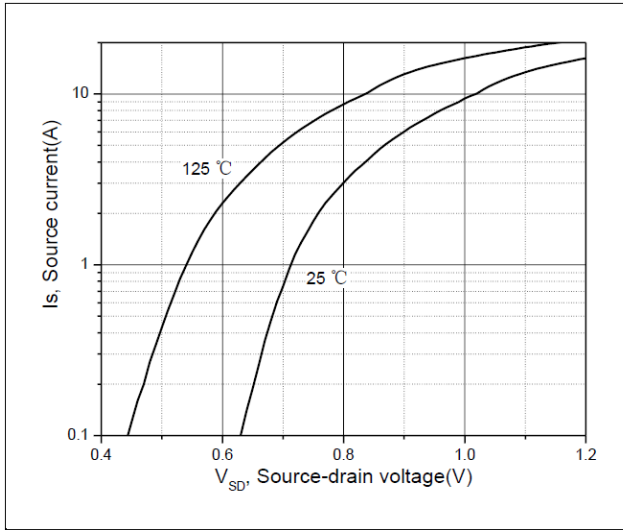


Figure 7, Forward characteristics of body diode

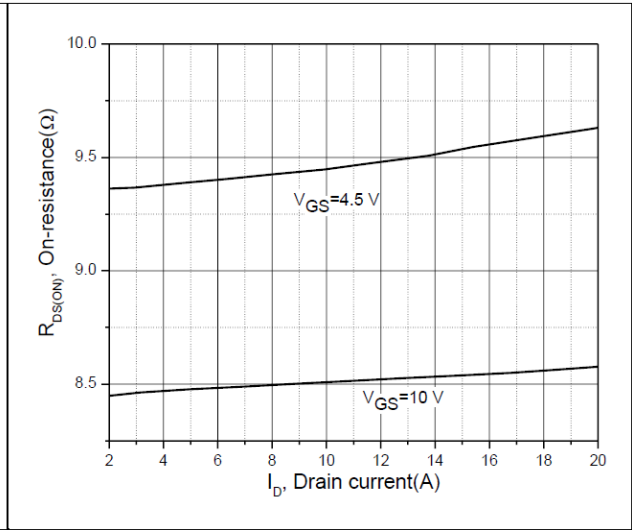


Figure 8, Drain-source on-state resistance

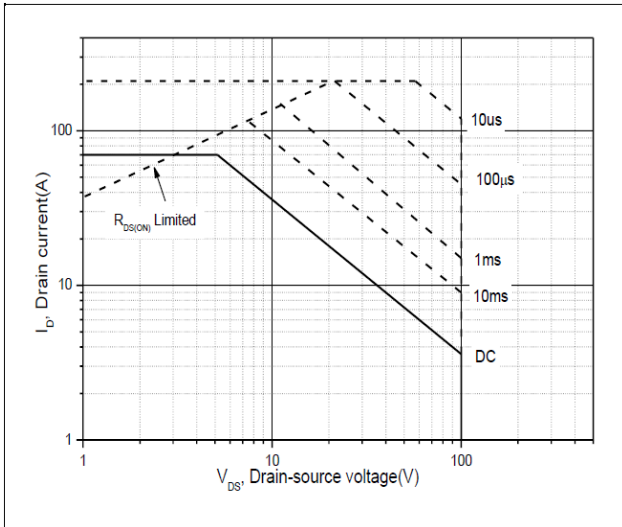


Figure 9, Safe operation area  $T_C=25^\circ\text{C}$

### Test circuits and waveforms

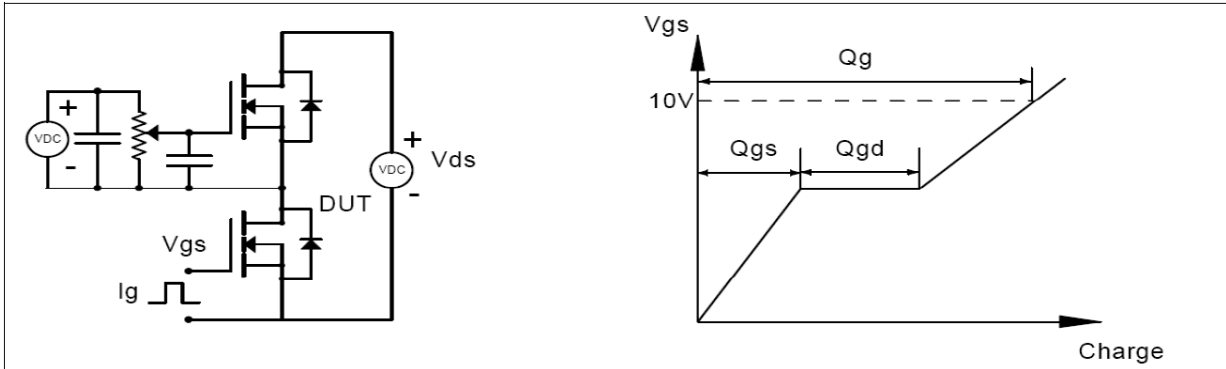


Figure 1, Gate charge test circuit & waveform

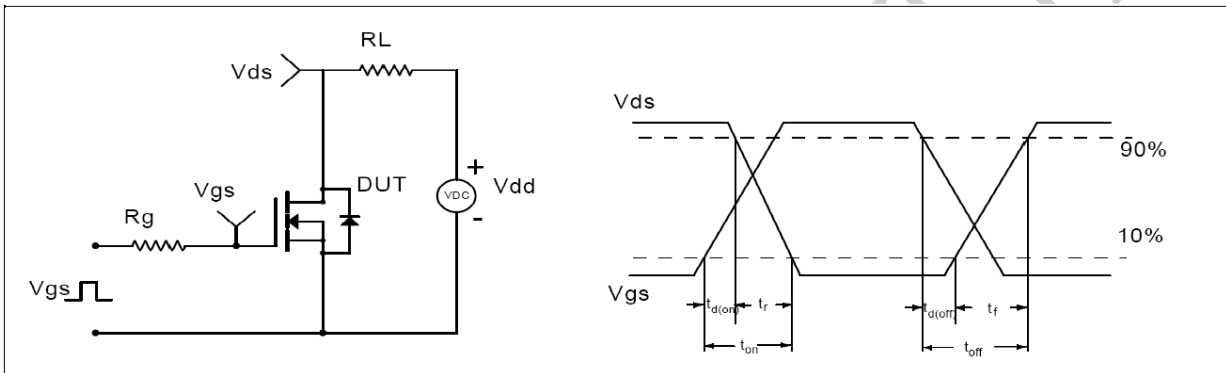


Figure 2, Switching time test circuit & waveforms

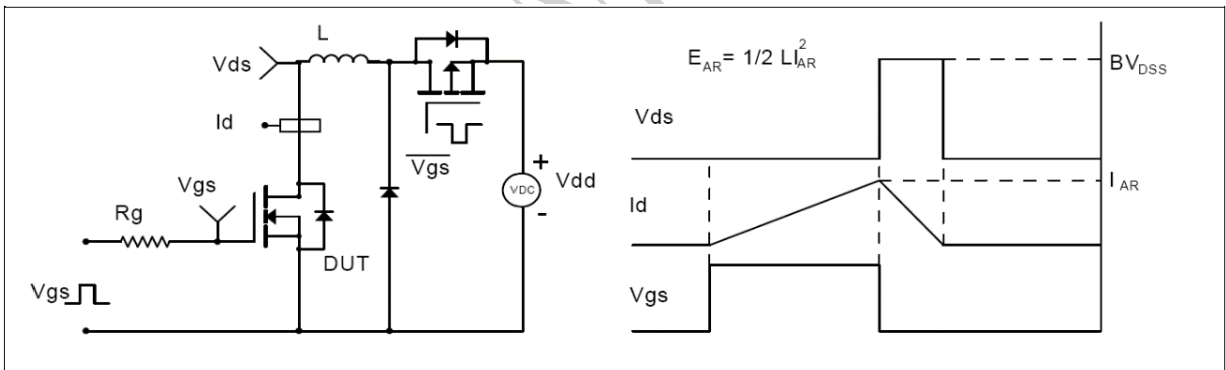


Figure 3, Unclamped inductive switching (UIS) test circuit & waveforms

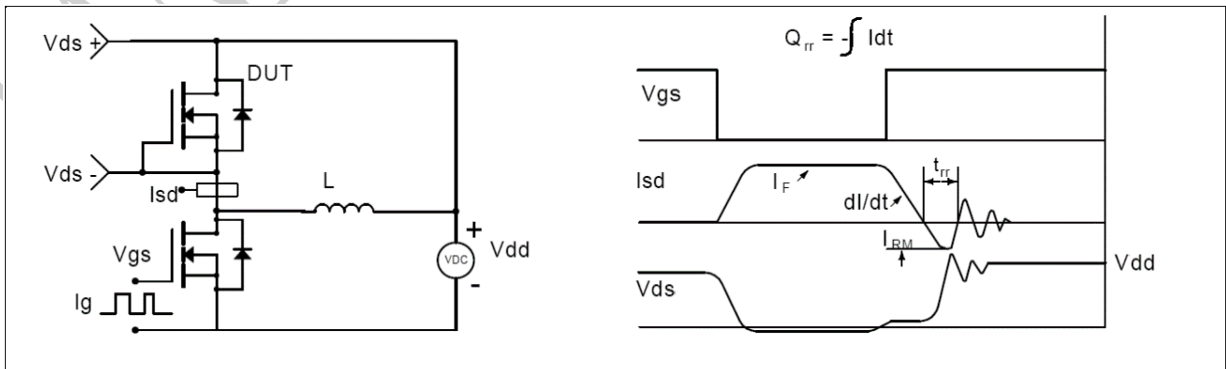
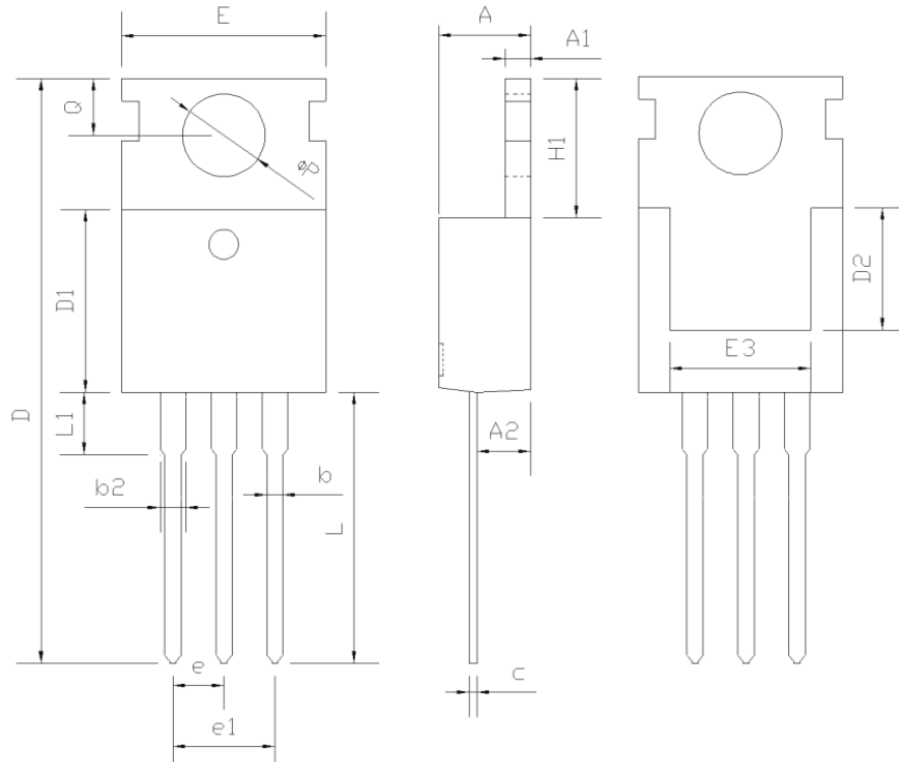


Figure 4, Diode reverse recovery test circuit & waveforms

## Package Information



Symbol	Min	Nom	Max
A	4.37	4.57	4.77
A1	1.25	1.30	1.45
A2	2.20	2.40	2.60
b	0.70	0.80	0.95
b2	1.17	1.27	1.47
c	0.40	0.50	0.65
D	15.10	15.60	16.10
D1	8.80	9.10	9.40
D2	5.50	-	-
E	9.70	10.00	10.30
E3	7.00	-	-
e	2.54 BSC		
e1	5.08 BSC		
H1	6.25	6.50	6.85
L	12.75	13.50	13.80
L1	-	3.10	3.40
ΦP	3.40	3.60	3.80
Q	2.60	2.80	3.00